Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10776527	CHEN, CHIH-WEI
Examiner	Art Unit
Keefer, Michael E	2154

SEARCHED							
Class		Subclass	Date Date	Examiner			
709	220		8/14/2007	MEK			

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST Search	8/14/2007	MEK	
Consulted Examiner Dustin Nguyen	8/13/2007	MEK	
Google Search	8/14/2007	MEK	
709/220-222 keyword limited	8/14/2007	MEK	

INTERFERENCE SEARCH					
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